

***Radiation Safety & Control Services,
Inc.***

**Introduction to Uncertainty
Calculations in Instrument
Calibrations**

Health Physics Society Annual Meeting

Professional Enrichment Program Continuing
Education Lecture

Dallas, Texas

J. P. Tarzia, M.S., CHP

February 7, 2012



Terminal Objective

To understand the basic concepts of
determining the total uncertainty in exposure
rate for instruments calibrated using gamma-
emitting sources



Enabling Objectives

- Define the concept of accuracy and precision
- List some major factors which affect instrument accuracy
- Identify both systematic and random errors associated with instrument calibrations
- Understand the method for calculating instrument response and its associated error
- Understand how the accuracy criteria is applied to the calibration process



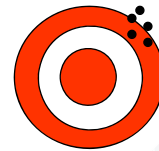
Outline

- General Calibration Process
- Uncertainty Parameters
- Determining Source Exposure Rate Uncertainty
- Determining Random and Systematic Uncertainty in Detector Measurements
- Determining Total Uncertainty in Measurement Results



Accuracy and Precision

- **Accuracy:** a measure of how well a true quantity is estimated, measured value/true value.
- **Precision:** a measure of reproducibility



Instrument Calibrations

- Calibration goal is to provide a calibration that will yield an “acceptably accurate” estimate of the desired quantity (i.e. exposure or dose rate) when used in the field
- To determine that a calibration is “acceptably accurate” one must know the uncertainty in the measurement



Types of Uncertainty

- **Random:** Uncertainties in the random variations in the measurement process that quantifies the precision
- **Systematic:** Uncertainties that cannot be estimated by statistical methods



Random Uncertainties

Random uncertainties can be calculated using the following equation:

$$\delta_{\text{Random}} = t * \sigma_R$$

Where:

- t = Student t value for particular degrees of freedom to yield a given probability that the true value X will be included in the confidence interval
- σ_R = Standard Deviation in the value with random error



Value of Student t-factor

Degrees of Freedom, n-1	Probability			
	0.50	0.90	0.95	0.99
1	1.000	6.31	12.71	63.7
2	0.816	2.92	4.30	9.92
3	0.765	2.35	3.18	5.84
4	0.741	2.13	2.78	4.60
5	0.727	2.02	2.57	4.03
6	0.718	1.94	2.45	3.71
7	0.711	1.90	2.36	3.50
9	0.703	1.83	2.26	3.25
14	0.692	1.76	2.14	2.98
19	0.688	1.73	2.09	2.86
29	0.683	1.70	2.04	2.76
49	0.679	1.68	2.01	2.68
99	0.677	1.66	1.98	2.63
∞	0.674	1.64	1.96	2.58

Reference: NCRP 112, Table 2.2



Systematic Uncertainties

- May result from a number of causes
 - Errors in reading instrument response
 - Source to detector distance errors
 - Attenuator placement errors
- May be positive or negative
- May not be normally distributed
- Should try to be eliminated by investigation and correction



Systematic Uncertainties

- Systematic uncertainties can be estimated by determining the apparent standard deviation, u
- The apparent standard deviation, u , can be estimated as 1/3 of the maximum systematic uncertainty
- For 95% confidence, $2u$ is the range of uncertainty around the mean



Overall Uncertainty

- Systematic uncertainty standard deviation $u = \frac{\delta \text{SysMax}}{3}$
- Random uncertainty standard deviation σ_R
- Overall Uncertainty $\pm \left[(t\sigma_R)^2 + (ku)^2 \right]^{\frac{1}{2}}$
 - The value of k at the 95% confidence level is 2



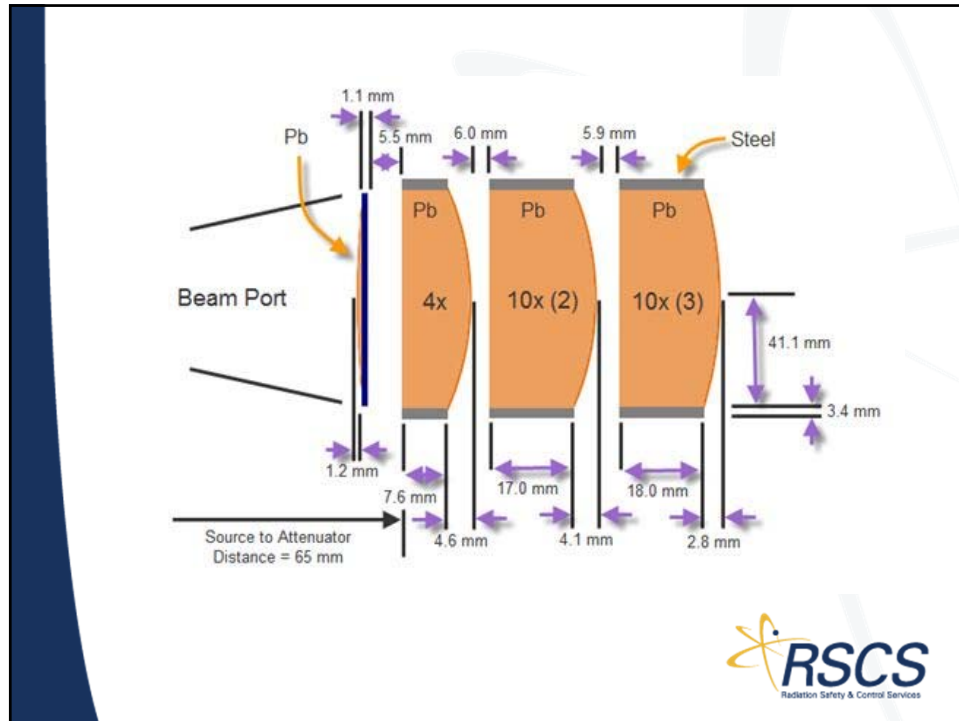
Case Study in Determining Exposure Rate Calibration Uncertainty



Assumptions Used

- Cs-137 Calibration Beam Source installed on track system
- 3 attenuator used in multiple combinations
- Multiple instruments calibrated
 - Ion Chambers
 - GM Detectors
 - Scintillation Detectors
 - Solid State Detectors





Uncertainty Evaluation

- Evaluate the “true” exposure rate and potential uncertainties in the “true” values assumed
- Evaluate the potential uncertainties in various parameters associated with calibration of each type of instrument
 - Random
 - Systematic

Evaluate the “true” Exposure Rate and its Uncertainty

- Use a transfer standard instrument such as an Exradin Shonka – Wychoff ionization chamber¹ or HPIC for low dose rates
 - ¹Used with a calibrated electrometer system to measure current
- Transfer Standards calibrated and traceable to the National Institute of Standards



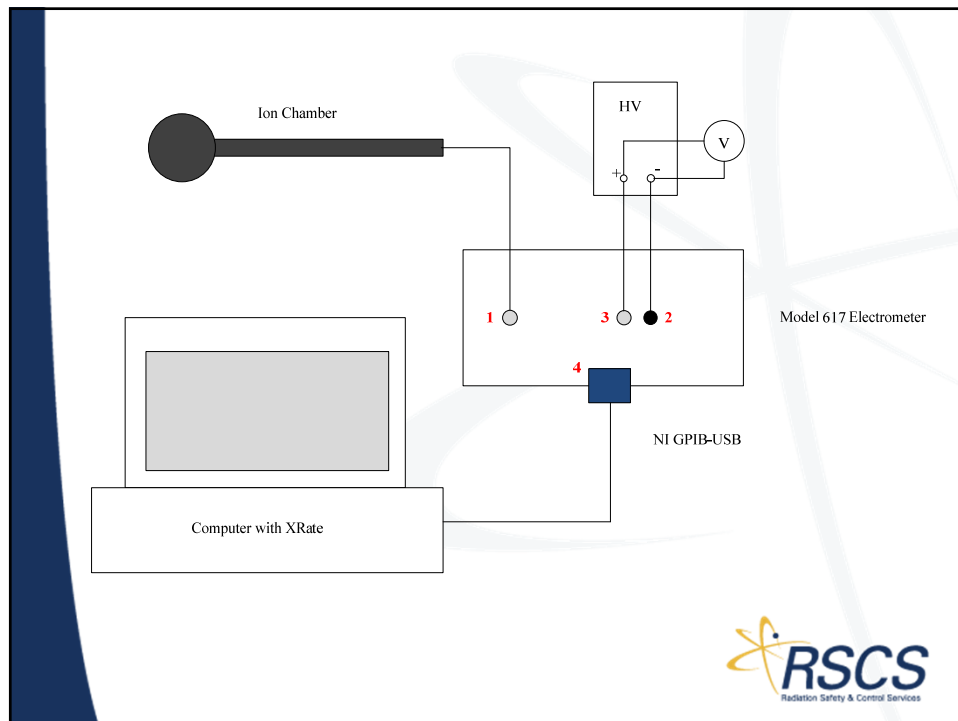
Uncertainty Evaluation

- Review of measurement process identified both random and systematic errors associated with determination of true exposure rates
- Radom Error
 - Associated with the statistical results of the transfer instruments
- Systematic Errors
 - Detector Placement (distance)
 - Ion Chamber Calibration
 - Electrometer Calibration
 - Temperature
 - Pressure
 - Exposure rate curve fit (residuals)

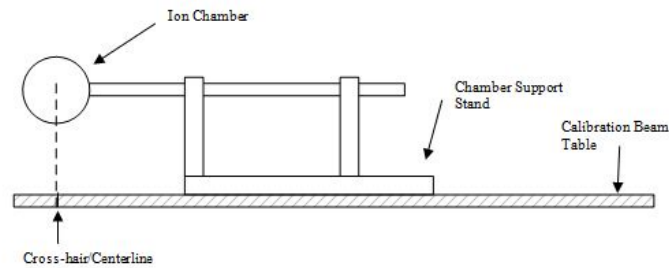


Evaluation of “true” Exposure Rate

- Background measurements recorded using a lead shield in front of the source
- Unattenuated and attenuated measurements taken at source to center of detector at distances of 30, 50, 80, 100, 200, 300 cm
- Six measurements taken at each locations and averaged to yield exposure rate at each location



Reference Chamber Support



Exposure Rate Curve Development

- Exposure rates plotted and a power trend line created to get the base and exponential values of the experimental measurements
- Power equation fit yields correlation coefficients $\dot{X} = a * x^b$
- Percent residuals determined between the fit functions and the measured data



Exposure Rate Power Functions

Beam			
Source	Base	Exponent	Corr. Fit
Attenuator	a	b	r^2
1x	6.279100E+02	-2.004660E+00	9.999627E-01
4x	1.345762E+02	-1.973129E+00	9.999258E-01
10x2	6.621852E+01	-2.016499E+00	9.999716E-01
10x3	6.417209E+01	-1.999544E+00	9.999254E-01
40x2	2.215078E+01	-2.060330E+00	9.996309E-01
40x3	1.783889E+01	-2.008843E+00	9.993982E-01
100x	9.883114E+00	-2.059398E+00	9.986914E-01
400x	1.605974E+00	-1.938399E+00	9.994158E-01

$$\dot{X} = a * x^b$$



Table of Residuals

Distance (cm)	30 (A6)	50 (A6)	80 (A6)	100 (A6)	100 (PIC)	200 (PIC)	300 (PIC)
1x	-0.268%	1.192%	-0.382%	-0.250%	-0.124%	-1.440%	1.300%
4x	0.795%	-1.250%			1.201%	-2.149%	1.455%
10x2	-0.024%				-0.508%	1.528%	-0.979%
10x3	1.090%				-2.564%	0.889%	0.631%
40x2					0.943%	-2.511%	1.617%
40x3					1.161%	-3.079%	1.992%
100x					1.761%	-4.618%	3.029%
400x					1.103%	-2.929%	1.893%



Overall Random Uncertainty

$$\delta_{\text{Random}} = t * \sigma_R$$

$$\sigma_R = R \sqrt{\left(\frac{\sigma_I}{I}\right)^2}$$

σ_R = Standard deviation in cal value

σ_I = Standard deviation in the mean instrument response

T = True calibration value

I = Mean of instrument response

$$R = \frac{I}{T} = 1$$



Overall Random Uncertainty

$$\sigma_R = \left(\frac{\sigma_{\bar{I}}}{\bar{I}}\right) = \frac{\sqrt{\frac{\sum_{i=1}^N (I_i - \bar{I})^2}{(N-1)}}}{\bar{I}}$$



Overall Random Uncertainty

- Several measurements using various attenuators and distance used to compute relative errors
- Maximum relative error used in overall random uncertainty calculation



Random Uncertainties Associated with Beam Measurements

Attenuation	# Trials	100 cm				200 cm				300 cm			
		Rel. Error	t-value	Uncertainty		# Trials	Rel. Error	t-value	Uncertainty	# Trials	Rel. Error	t-value	Uncertainty
1x	6	0.0014	2.4469	0.0034		6	0.0008	2.4469	0.0020	6	0.0009	2.4469	0.0021
4x	6	0.0012	2.4469	0.0028		6	0.0021	2.4469	0.0050	6	0.0019	2.4469	0.0046
10x2	6	0.0008	2.4469	0.0019		6	0.0014	2.4469	0.0033	6	0.0014	2.4469	0.0035
10x3	5	0.0011	2.5706	0.0028		6	0.0035	2.4469	0.0086	6	0.0021	2.4469	0.0051
40x2	6	0.0025	2.4469	0.0060		6	0.0024	2.4469	0.0058	6	0.0036	2.4469	0.0088
40x3	6	0.0075	2.4469	0.0184		6	0.0014	2.4469	0.0034	7	0.0030	2.3646	0.0071
100x	2	0.0040	4.3027	0.0174		2	0.0011	4.3027	0.0047	6	0.0045	2.4469	0.0110
400x	6	0.0036	2.4469	0.0088		7	0.0080	2.3646	0.0190	6	0.0082	2.4469	0.0200
Maximum Uncertainty		0.0200											

Note: 0.0082 (0.82%) was the largest observed relative error



Overall Random Uncertainty

$$\delta_{\text{Random}} = t * \sigma_R$$

$$\delta_{\text{Random}} = 2.447 * 0.0082$$

$$\delta_{\text{Random}} = 2.0\%$$



Systematic Uncertainties

$\delta_{\text{distance max}}$ = maximum error associated with distance = 3.9%

δ_{distance} = 2 sigma (95% confidence) error associated with distance = $2\left(\frac{3.9\%}{3}\right) = 2.6\%$

$\delta_{\text{ion chamber}}$ = 2 sigma (95% confidence) error associated with ion chamber calibration = 1.6%

$\delta_{\text{Electrometer}}$ = 2 sigma (95% confidence) error associated electrometer calibration = 0.20%



Systematic Uncertainties

$\delta_{\text{temperature}}$ = 2 sigma (95% confidence) error associated with temperature monitoring device calibration (+/- 1.0 c) = 0.34%

δ_{pressure} = 2 sigma (95% confidence) error associated with pressure monitoring device calibration = 1.0%

$\delta_{\text{residuals max}}$ = maximum error associated with curve fit residuals = 4.4%

$\delta_{\text{residuals}}$ = 2 sigma (95% confidence) error associated with curve fit residuals = $2\left(\frac{4.4\%}{3}\right) = 2.9\%$



Overall Systematic Uncertainty

$$\pm_{\text{systematic}} = \sqrt{\left(k \frac{\delta_{\text{distance max}}}{3}\right)^2 + (\delta_{\text{ion chamber}})^2 + (\delta_{\text{electrometer}})^2 + (\delta_{\text{temperature}})^2 + (\delta_{\text{pressure}})^2 + \left(k \frac{\delta_{\text{residuals max}}}{3}\right)^2}$$

$$= 4.3\%$$



Overall Total Uncertainty in Exposure Rate

$$\pm_{total} = \sqrt{(\pm_{random})^2 + (\pm_{systematic})^2} = 4.8\%$$



Total Uncertainty in Instrument Calibration

- Requires knowledge of “true” beam exposure uncertainty and meter uncertainties
 - Meter distance placement
 - Meter reading
 - Pressure and temperature (for unsealed detectors only)
- Calibration uncertainty is a combination of exposure uncertainty and meter uncertainties



Meter Uncertainties

- Meter placement
 - Can be estimated to be the same as the ion chamber distance uncertainty
- Meter reading
 - Can be ascertained experimentally by taking a series of meter reading by different individuals and calculating the standard deviation
 - Can be ascertained by assuming a maximum error in meter reading
- Pressure and Temperature
 - Can be assumed to be the same uncertainties as used to calculate total exposure uncertainty
- Other uncertainties related to calibration specific calibration conditions



Meter Reading Uncertainties

	Distance	Measurer 1	Measurer 2	Measurer 3
1 R 44-9	16.6	16.4	16.5	16.7
1 R 44-6	16.6	16.4	17	16.5
1 R ND2000	16.6	17	16.5	17.2
1 R DMC-2000	16.6	16.8	16.6	16.9
200 mR 44-9	37.1	36.8	37.3	36.8
200 mR 44-6	37.1	37	37.2	37.1
200 mR ND2000	37.1	37.2	37	37.8
200 mR DMC-2000	37.1	36.8	37.1	37.3
40 mR 44-9	82.9	82.9	82.8	83
40 mR 44-6	82.9	82.1	82.2	82.7
40 mR ND2000	82.9	83	82.5	83
40 mR DMC-2000	82.9	82.8	82.7	83.1



Meter Reading Uncertainties

- The average error for all measurements is 0.75%
- The maximum error for an individual measurement (at the 16.6 cm distance) = 3.61%
- The standard deviation in meter reading can be estimated as $\sigma_{Meter} = \frac{\delta_{Meter_Max}}{3} = \frac{3.61}{3}$
- The 95% probability in meter read uncertainty can be calculated as $2\sigma_{Meter} = 2.4\%$



Total Calibration Uncertainty

$$\sqrt{\delta_{total\ exposure}^2 + \delta_{meter\ reading}^2 + \delta_{temp}^2 + \delta_{pressure}^2 + \delta_{distance}^2}$$



Note: For sealed or non-gas-filled detectors, the temperature and pressure errors can be negligible



Total Calibration Uncertainty

δ_{Exposure}	=	2 sigma (95% confidence) uncertainty in exposure = 4.3% (from previous analysis)
δ_{Meter}	=	2 sigma (95% confidence) uncertainty in meter reading = 2.4% (from previous analysis)
$\delta_{\text{Temperature}}$	=	2 sigma (95% confidence) error associated with temperature monitoring device calibration (+/- 1.0 c) = 0.34%
δ_{Pressure}	=	2 sigma (95% confidence) error associated with pressure monitoring device calibration = 1.0%
δ_{Distance}	=	2 sigma (95% confidence) error associated with distance = 2.6%



Total Calibration Uncertainty

$$\pm \sqrt{(0.043)^2 + (0.024)^2 + (0.0034)^2 + (0.01)^2 + (0.026)^2}$$

$$\pm 5.7\%$$

